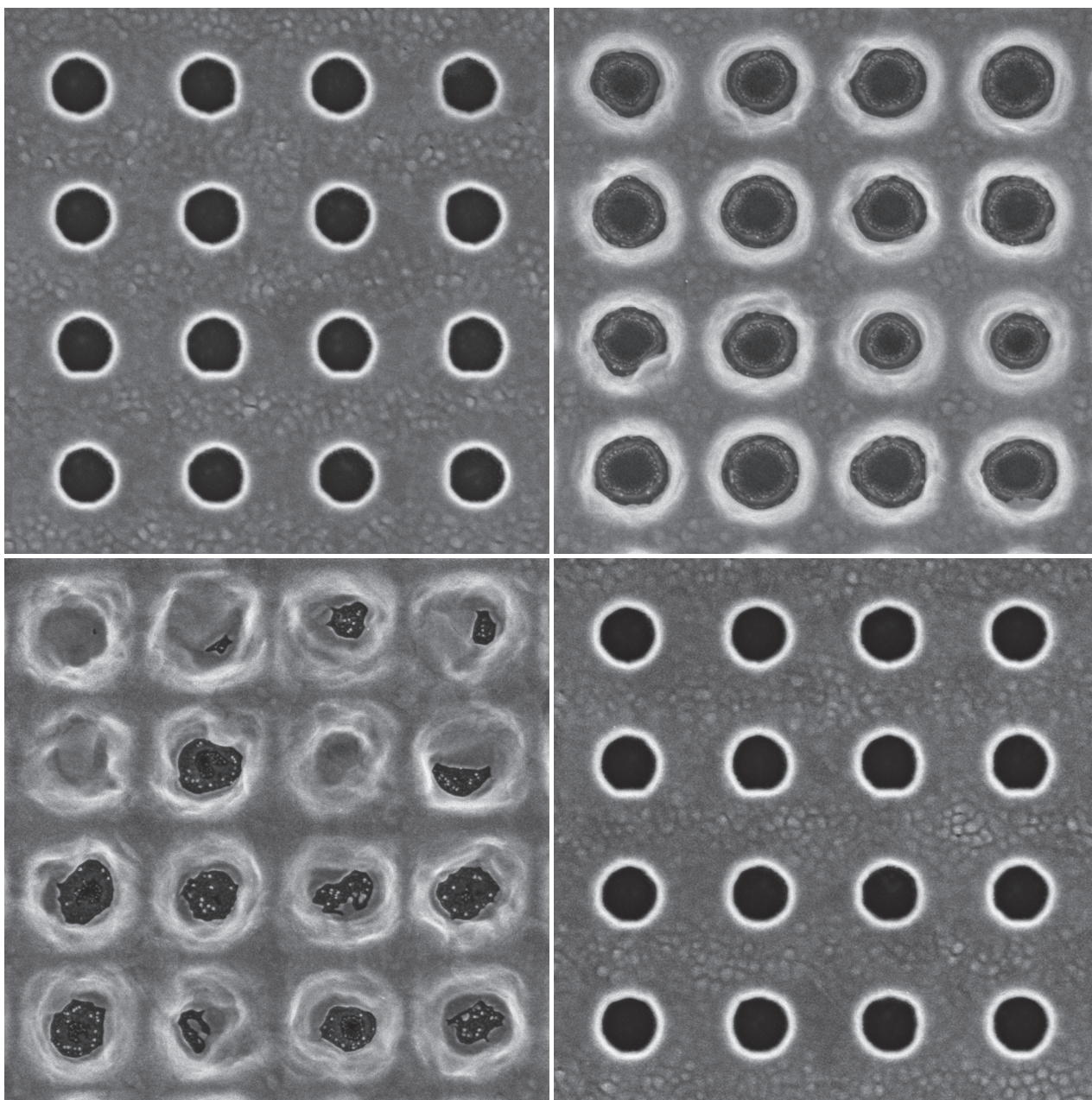


# Microscopy TODAY

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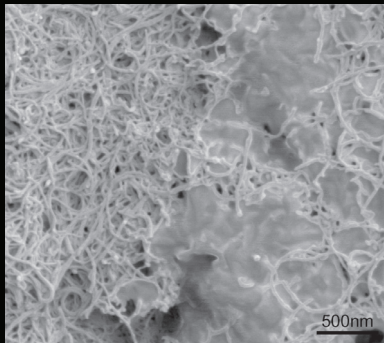


# The Ultimate SEM Is Here!

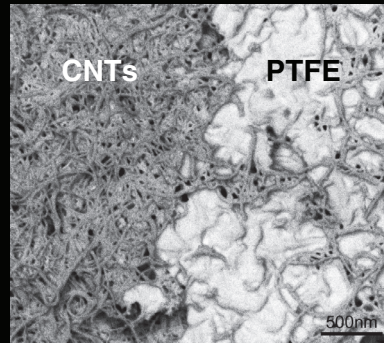
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- Increased probe current for S/N and analytical performance.
- Unparalleled imaging throughput with improved CFE beam stability.
- Enhanced deceleration and new selective energy filter provide fine contrast differentiation of similar atomic number materials at low accelerating voltages.



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Sample: Carbon Nanotube (CNT) and Polytetrafluoroethylene (PTFE) composite film (protective film used for fuel cell) Sample Courtesy of Prof. Yoshiyuki SHOW, School of Engineering, Tokai University, Japan

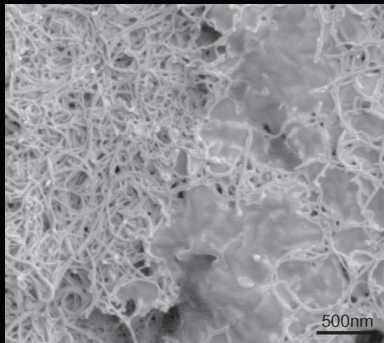


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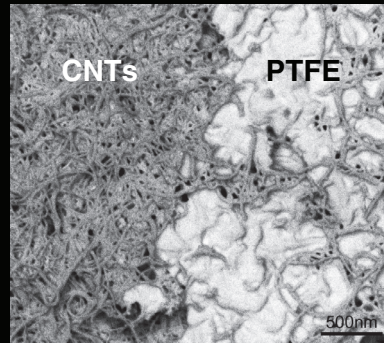
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**Image at Top:** Cathodoluminescence image of composite SiC-diamond cutting tool; Colin MacRae, CSIRO-Minerals, Clayton, Victoria, Australia



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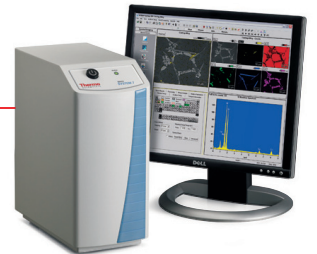
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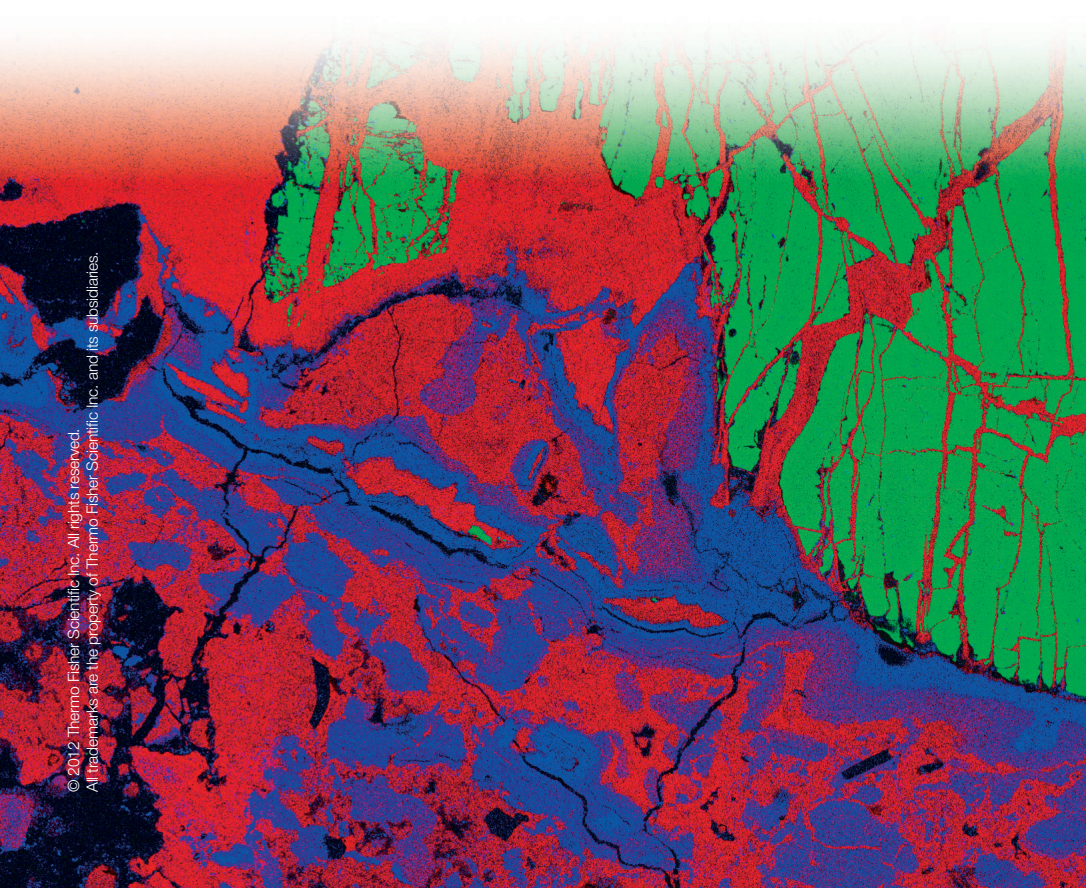
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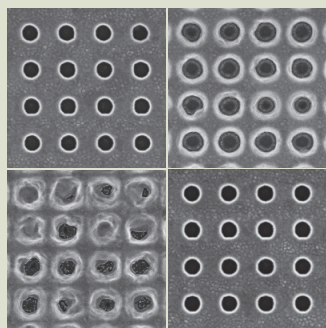
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### About the Cover



SEM images of a pattern produced with a FIB beam: focused (upper left), unfocused (middle images), and focused with a lens correction (lower right). Image width = 1950 nm.

See article by Schuetze.



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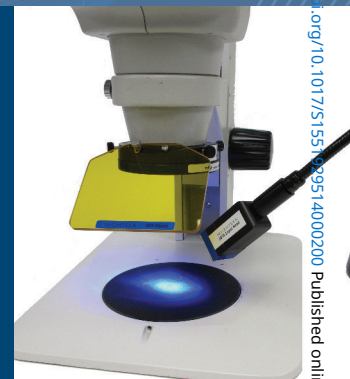
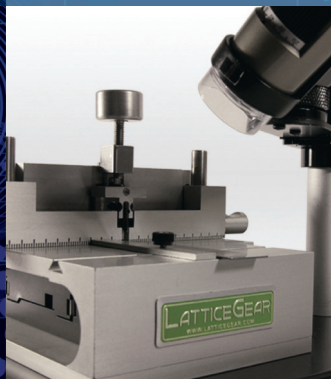
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